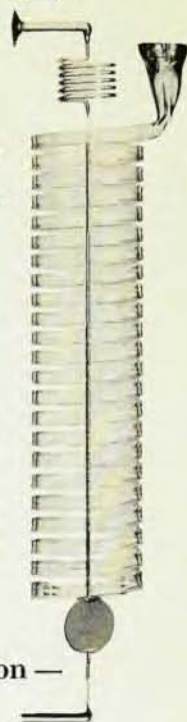


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Jonscher, Physics Department, Chelsea College of Science and Technology, London SW 3. Application forms will be available in July from the Meetings Officer, Institute of Physics and the Physical Society, 47 Belgrave Square, London SW 1, England.

Vacuum

Experimental and theoretical papers on the production, measurement, and application of vacuum are solicited for the 12th National Vacuum Symposium to be held September 29 to October 1 at the Statler-Hilton Hotel in New York City. The American Vacuum Society's program committee lists the following topics as particularly welcome: fundamental aspects of vacuum, including the behavior of materials and surfaces in a vacuum environment; new or improved components and systems; space-related problems; electron-microscope inspection of microcircuits; and thin films.

In addition, on the day preceding the conference, the AVS Thin Film Division will hold a special symposium of invited papers on such topics as nucleation and growth, dislocations, and low-energy electron diffraction studies.

Abstracts, limited to 150 words, double-spaced in a single paragraph, should be sent in triplicate by July 5 to R. L. Jepsen, Varian Associates, 611 Hansen Way, Palo Alto, Calif. Address inquiries to H. W. Schleuning, Polytechnic Institute of Brooklyn, 333 Jay Street, Brooklyn, N. Y.

Nuclear science

The Institute of Electrical and Electronics Engineers will hold its 12th nuclear science symposium in San Francisco from October 18 to 20.

Papers are invited on nuclear detectors, instruments, on-line data processing and control for high-energy and space physics, space power and propulsion development, and power and research reactor operation. Abstracts, 100 to 300 words, must be sent by July 1 to J. M. Harrer, Argonne National Laboratory, Argonne, Ill. Other correspondence should be addressed to J. J. Kennedy, General Electric Company, Mis-

sile and Space Division, Valley Forge Space Technology Center, PO Box 8555, Philadelphia, Pa.

Engineering science

Manuscripts describing theoretical and experimental research in the various fields of engineering science—physics, chemistry, and mathematics—are being solicited for the third technical meeting of the Society of Engineering Science. To be held November 3 to 5 at the University of California's Davis campus, the meeting will emphasize significant interdisciplinary studies, but due consideration will also be given to work in highly specialized fields.

The deadline for submission of manuscripts, which should conform to the format specified in the *International Journal of Engineering Sciences* is July 1. Three copies should be sent to Professor A. C. Eringen, School of Aeronautics, Astronautics, and Engineering Sciences, Purdue University, Lafayette, Ind. Additional information regarding the meeting can be obtained from Dr. Edward Teller, Department of Applied Science, University of California, Davis.

Reliability

The fourth annual symposium on the physics of failure in electronics will meet November 16 to 18 in Chicago under the joint auspices of the Rome Air Development Center and IIT Research Institute.

The emphasis of the meeting will be on the identification of the fundamental physical and chemical processes contributing to the degradation of electronic parts and materials, and their interpretation and application to device reliability. The technical sessions will cover such topics as principles and applications, test analysis and correlation, surface effects, effects in films, bulk effects, etc. June 25 is the deadline for abstracts of contributed papers.

Information regarding the submission of abstracts and attendance at the symposium can be obtained from Morton E. Goldberg, IIT Research Institute, 10 West 35th Street, Chicago, Ill.